

STATIC RAM **64K × 32 2M BIT**

Type name	Max. Access time (ns)	Load memory	Outward dimensions W × H × D (mm)	Data sheet page
MH6432NZ-15	15	M5M5258BJ × 8	92.71 × 17.6 × 8.9	3/8
MH6432NZ-20	20			
MH6432NZ-25	25			
MH6432NZ-35	35			
MH6432NZ-20L	20			
MH6432NZ-25L	25			
MH6432NZ-35L	35			
COMMON DATA				4/8

MITSUBISHI LSIs <SRAM MODULE>

MH6432NZ-15,-20,-25,-35, -20L,-25L,-35L

2097152-BIT(65536-WORD BY 32-BIT)CMOS STATIC RAM

DESCRIPTION

The MH6432NZ is a 2097152 bits CMOS static RAM module organized as 65536 words by 32-bits. It consists of eight industry standard 64K × 4 static RAMs.

The stand-by current is low enough for a battery back-up application. It is mounted a soj package on a 64-pin Zig-Zag in line package.

FEATURES

Type name	Access time (max)	Power dissipation	
		Active (typ)	Stand by (typ)
MH6432NZ-15	15ns	2400mW	40mW
MH6432NZ-20	20ns		
MH6432NZ-25	25ns		
MH6432NZ-35	35ns		
MH6432NZ-20L	20ns		400μW
MH6432NZ-25L	25ns		
MH6432NZ-35L	35ns		

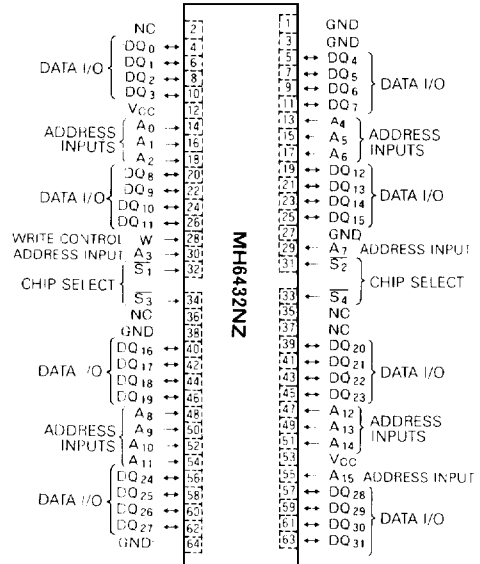
- Single +5V Power Supply
- No Clocks, No Refresh
- Directly TTL Compatible: All Inputs and Outputs
- Simple Memory Expansion by $\overline{S}$
- Common Data I/O
- Power down by $\overline{S}$
- Solder dipping lead

APPLICATION

High-speed memory systems

PIN CONFIGURATION (TOP VIEW)

[Both side]



Outline 64N5

NC: NO CONNECTION

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FUNCTION

A write operation is executed during the $\overline{S}$ low and $\overline{W}$ low overlap time. In this period, address signals must be stable. When $\overline{W}$ is low, the DQ terminal is maintained in the high impedance state.

In a read operation, after setting $\overline{W}$ to high, and $\overline{S}$ to low if the address signals are stable, the data is available at the DQ terminal.

When $\overline{S}$ is high, the chip is in the non-selectable state, disabling both reading and writing. In this case the output is in the floating (high-impedance) state, useful for OR-ties with other devices.

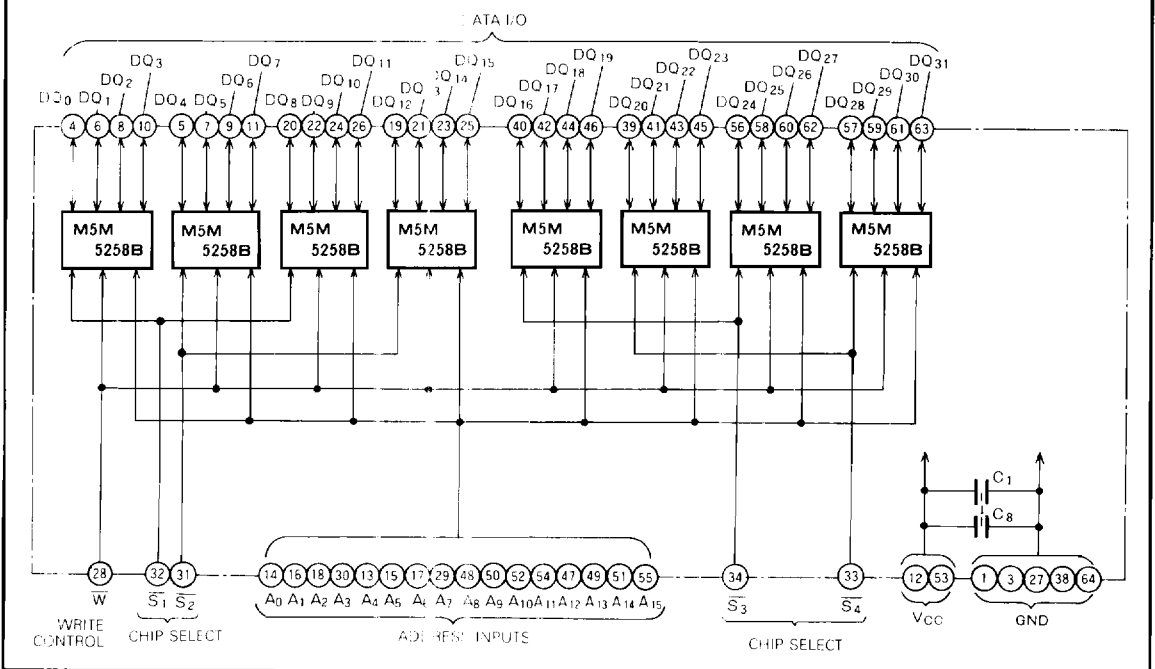
Single $\overline{S}$ controls the power-down feature. When $\overline{S}$ goes high, power dissipation is reduced extremely. The access time from $\overline{S}$ is equivalent to the address access time.

MODE SELECTION

$\overline{S}$	$\overline{W}$	Mode	Data I/O	I _{cc}
H	X	Non selection	High-impedance	Stand-by
L	L	Write	D _{IN}	Active
L	H	Read	D _{OUT}	Active

H : V_{IH} L : V_{IL} X : V_{IL} or V_{IH}

BLOCK DIAGRAM



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ABSOLUTE MAXIMUM RATINGS

Symbol	Parameter	Conditions	Ratings	Unit
V_{CC}	Supply voltage	With respect to GND	$-3.5 \sim 7$	V
V_I	Input voltage		$-3.5 \sim 7$	V
V_O	Output voltage		$-3.5 \sim 7$	V
P_d	Maximum power dissipation		8	W
T_{opr}	Operating temperature		$0 \sim 70$	°C
T_{stg}	Storage temperature		$-40 \sim 125$	°C

* 1: Pulse width ≤ 20 ns. In case of DC: ≤ 0.5 V

DC ELECTRICAL CHARACTERISTICS ($T_a = 0 \sim 70^\circ\text{C}$, $V_{CC} = 5\text{V} \pm 10\%$, Unless otherwise noted)

Symbol	Parameter	Test conditions	Limits			Unit
			Min	Typ	Max	
V_{IH}	High-level input voltage		2.4		$V_{CC} + 0.3$	V
V_{IL}	Low-level input voltage		-0.5^*		0.6	V
V_{OH}	High-level output voltage	$I_{OH} = -4\text{mA}$	2.4			V
V_{OL}	Low-level output voltage	$I_{OL} = 8\text{mA}$			0.4	V
	Input current	$V_I = 0 \sim V_{CC}$			16	μA
$ I_{OZ} $	Off-state output current	$V_I(\bar{S}) = V_{IH}$, $V_O = 0 \sim V_{CC}$			10	μA
I_{CC1}	Supply current from V_{CC}	$V_I(\bar{S}) = V_{IL}$ Output open	AC (15ns cycle)		1040	mA
			AC (20, 25ns cycle)		960	
			DC		560 680	
I_{CC2}	Stand-by current	$V_I(\bar{S}) = V_{IH}$	AC (15ns cycle)		400	mA
			AC (20, 25ns cycle)		320	
			Other $V \geq V_{IH}$ or $\leq V_{IL}$		240	
I_{CC3}	Stand-by current	$V_I(\bar{S}) = V_{CC} - 0.2\text{V}$ Other $V_I \leq 0.2\text{V}$ or $V_I \geq V_{CC} - 0.2\text{V}$	-15, -20, -25, -35		8 80	mA
			-20L, -25L, -35L		80 800	

Note 1: Current flow into an IC is positive, out is negative.

* -0.0V in case of AC (Pulse width ≤ 20 ns)

CAPACITANCE

Symbol	Parameter	Test conditions	Limits			Unit
			Min	Typ	Max	
C_i	Input capacitance	$V_I = \text{GND}$, $V_I = 25\text{mVrms}$, $f = 1\text{MHz}$			60	pF
C_o	Output capacitance	$V_O = \text{GND}$, $V_O = 25\text{mVrms}$, $f = 1\text{MHz}$			20	pF

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AC ELECTRICAL CHARACTERISTICS (Ta=0~70°C, VCC=5V±10%, unless otherwise noted)

(1) MEASUREMENT CONDITIONS

Input pulse levels $V_{IH}=3V$, $V_{IL}=0V$
 Input rise and fall time 3ns
 Input timing reference level
 $V_{IH}=2.4V$, $V_{IL}=0.6V$
 Output timing reference level
 $V_{OH}=2.0V$, $V_{OL}=0.8V$
 Output loads Fig. 1, Fig. 2

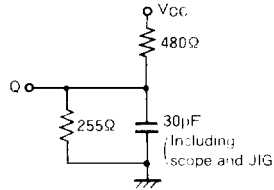


Fig. 1 Output load

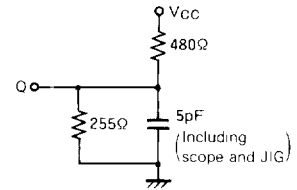


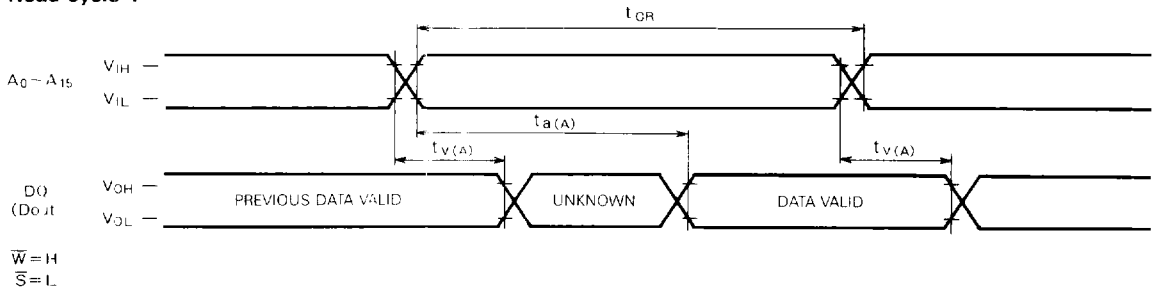
Fig. 2 Output load for t_{EN} , t_{dis}

(2) READ CYCLE

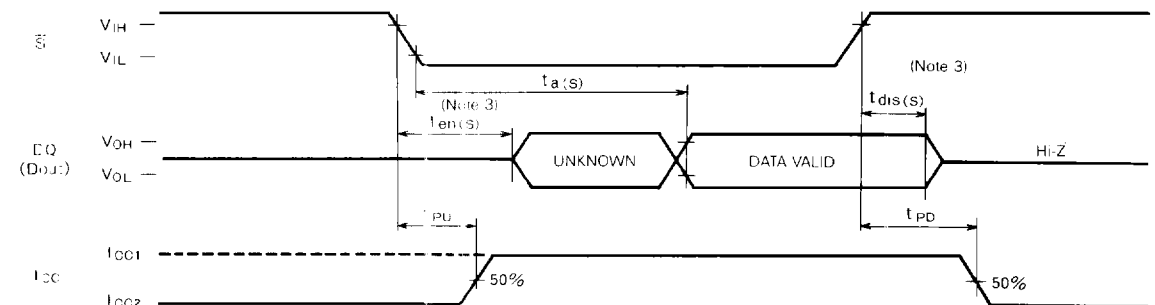
Symbol	Parameter	Limits												Unit
		MH6432NZ-15			MH6432NZ-20, -20L			MH6432NZ-25, -25L			MH6432NZ-35, -35L			
		Min	Typ	Max	Min	Typ	Max	Min	Typ	Max	Min	Typ	Max	
t _{CR}	Read cycle time	15			20			25			35			ns
t _{a(A)}	Address access time			15			20			25			35	ns
t _{a(S)}	Chip select access time			15			20			25			35	ns
t _{v(A)}	Data valid time after address	3			3			5			5			ns
t _{er_s}	Chip selection to output active	3			3			5			5			ns
t _{dis(S)}	Output disable time from CS	0		7	0		8	0		10	0		10	ns
t _{PU}	Power-up time after chip selection	0			0			0			0			ns
t _{PD}	Power down time after chip deselection			15			20			25			35	ns

(3) TIMING DIAGRAMS FOR READ CYCLE

Read cycle 1



Read cycle 2 (Note 2)



Note 2. Address valid prior to or coincident with $\bar{S}$ transition low.

3. Transition is measured $\pm 500mV$ from steady state voltage with specified loading in Figure 2.

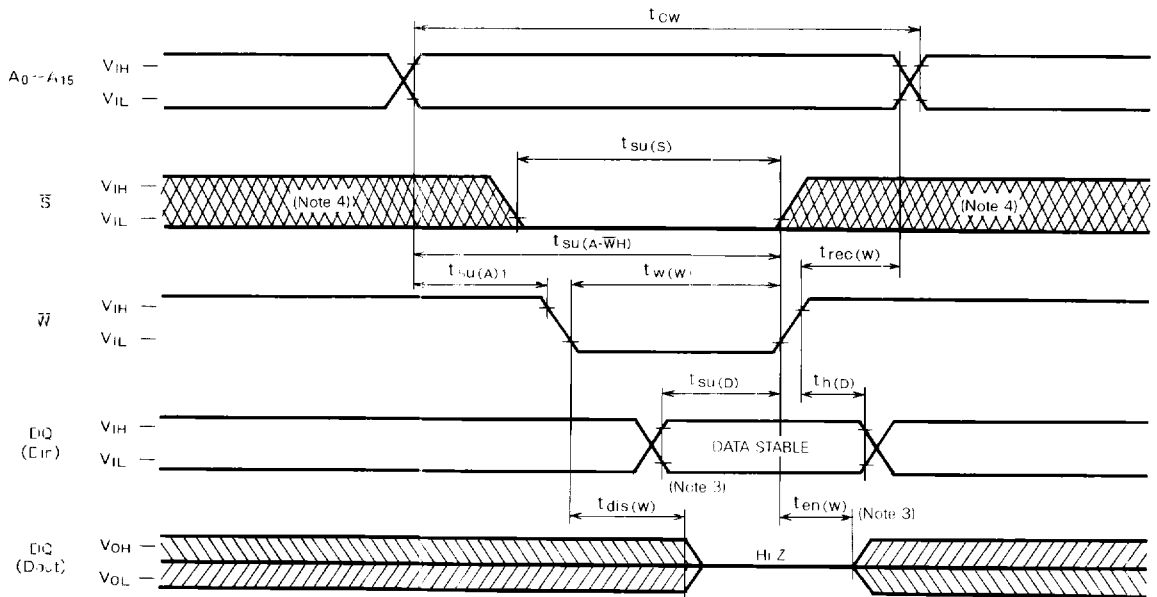
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(4) WRITE CYCLE

Symbol	Parameter	Limits												Unit
		MH6432NZ-15			MH6432NZ-20, -20L			MH6432NZ-25, -25L			MH6432NZ-35, -35L			
		Min	Typ	Max	Min	Typ	Max	Min	Typ	Max	Min	Typ	Max	
t _{CW}	Write cycle time	15			20			25			35			ns
t _{su(S)}	Chip select setup time	12			15			20			30			ns
t _{su(A)1}	Address setup time (W)	0			0			0			0			ns
t _{su(A)2}	Address setup time (S)	0			0			0			0			ns
t _{w(W)}	Write pulse width	12			15			20			25			ns
t _{rec(W)}	Write recovery time	0			0			0			0			ns
t _{su(D)}	Data setup time	7			8			10			15			ns
t _{h(D)}	Data hold time	0			0			0			0			ns
t _{dis(W)}	Output disable time from W	0		7	0		8	0		10	0		10	ns
t _{en(W)}	Output enable time from W	0			0			0			0			ns
t _{su(A-WH)}	Address to $\overline{W}$ high	12			15			20			30			ns

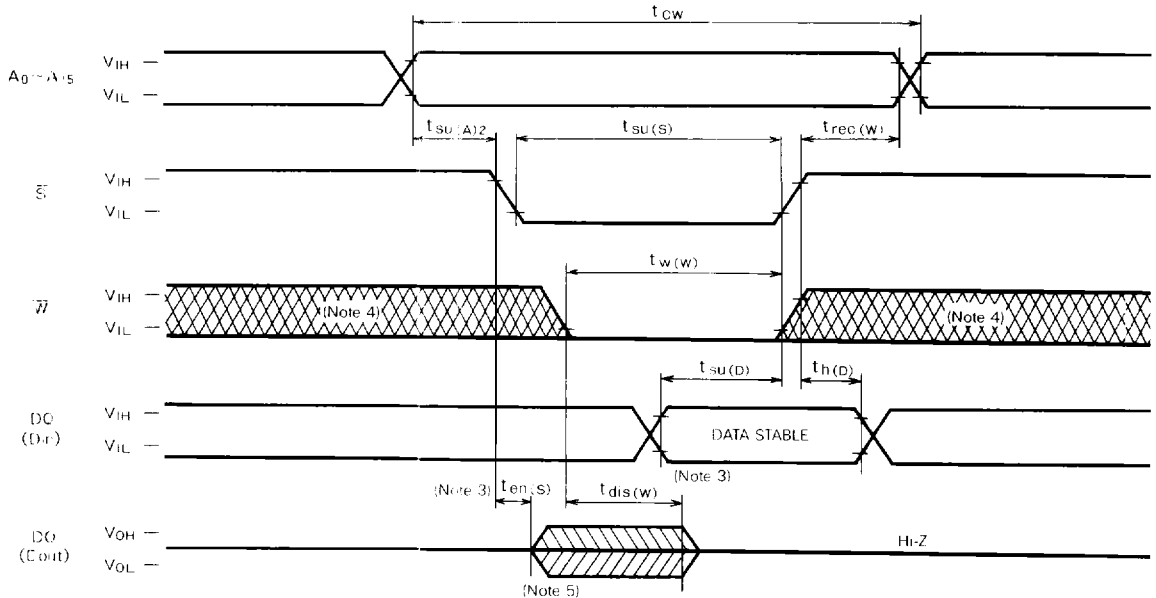
(5) TIMING DIAGRAMS FOR WRITE CYCLE

Write cycle 1 ($\overline{W}$ control mode)



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Write cycle 2 ($\overline{S}$ control mode)



Note 4: Hatching indicates the state is don't care

5: When the falling edge of $\overline{W}$ is simultaneous or prior to the falling edge of $\overline{S}$, the output is maintained in the high impedance

POWER DOWN CHARACTERISTICS ($T_a = 0 \sim 70^\circ\text{C}$, unless otherwise noted)

Symbol	Parameter	Test conditions	Limits			Unit
			Min	Typ	Max	
$V_{CC}(\text{PD})$	Power down supply voltage		2			V
$V_I(\overline{S})$	Chip select input voltage	$V_I(\overline{S}) \geq V_{CC} - 0.2\text{V}$	$V_{CC} - 0.2$			V
$t_{SU}(\text{PD})$	Power down setup time	$V_I \geq V_{CC} - 0.2\text{V}$ or $0\text{V} \leq V_I \leq 0.2\text{V}$	0			ns
$t_{REC}(\text{PD})$	Power down recovery time		-20L	20		ns
			-25L	25		
			-35L	35		
$I_{CC}(\text{PD})$	Power down supply current	$V_{CC} = 3.0\text{V}$			400	μA
		$V_{CC} = 5.5\text{V}$			800	

Note 6: This is only MH6432NZ: 20L, -25L, 35L

TIMING WAVEFORM FOR POWER DOWN

